



Challenging Methods and Applications for Smart Measurement Using Machine Vision

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Message from the Guest Editor

Dear Colleagues,

The widespread use of smart measures in several applications is the result of technological improvement. Machine vision (MV) is a technology and approach that enables automatic imaging-based inspection and analysis for a variety of industrial applications, including robot guidance and autonomous inspection. To enable measurements in each of these applications, sensors must be connected. Machine vision attempts to creatively combine already available technology and use them to address issues in the actual world. These kinds of technologies are becoming more prevalent in every aspect of daily life, including in the medical field, business, agriculture, smart cities, and smart health monitoring. We seek contributions that cover the most recent developments in measuring and instrumentation science and technology as well as machine vision advancements related to production, the use of smart materials, and measurement and estimation methods, among others.





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Message from the Editor-in-Chief

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